# $\frac{\text{MOSFET}}{\text{QFET}^{\text{\tiny{$\mathbb{R}$}}}} - \text{N-Channel}$ QFET<sup>®</sup> 600 V, 0.2 A, 11.5 $\Omega$

# FQT1N60CTF-WS

#### **Description**

This N-Channel enhancement mode power MOSFET is produced using ON Semiconductor's proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.

#### **Features**

- 0.2 A, 600 V,  $R_{DS(on)} = 9.3 \Omega$  (Typ.) @  $V_{GS} = 10$  V,  $I_D = 0.1$  A
- Low Gate Charge (Typ. 4.8 nC)
- Low Crss (Typ. 3.5 pF)
- 100% Avalanche Tested
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

#### **ABSOLUTE MAXIMUM RATINGS**

(T<sub>C</sub> = 25°C unless otherwise noted\*)

Symbol	Parameter		Value	Unit
V <sub>DSS</sub>	Drain to Source Voltage		600	V
$V_{GSS}$	Gate to Source Voltage		±30	V
I <sub>D</sub>	Drain Current Continuous (T <sub>C</sub> = 25°C) Continuous (T <sub>C</sub> = 100°C)		0.2 0.12	A
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	0.8	Α
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	33	mJ
I <sub>AR</sub>	Avalanche Current	(Note 1)	0.2	Α
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	0.2	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)		4.5	V/ns
P <sub>D</sub>	Power Dissipation (T <sub>C</sub> = 25°C) Derate above 25°C		2.1 0.02	W W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C
TL	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds		300	°C

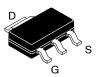
Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2. L = 59 mH,  $I_{AS}$  = 1.1 A,  $V_{DD}$  = 50 V,  $R_{G}$  = 25  $\Omega$ , Starting  $T_{J}$  = 25°C.
- 3.  $I_{SD} \le 0.2 \text{ A}$ ,  $di/dt \le 200 \text{ A/µs}$ ,  $V_{DD} \le BV_{DSS}$ , Starting  $T_J = 25^{\circ}\text{C}$ .

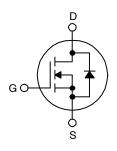


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SOT-223 CASE 318H-01



#### **MARKING DIAGRAM**



\$Y = ON Semiconductor Logo &Z = Assembly Plant Code &3 = 3-Digit Date Code Format &K = 2-Digit Lot Run Traceability Code

FQT1N60C = Specific Device Code ■ Pb-Free Package

(Note: Microdot may be in either location)

#### ORDERING INFORMATION

See detailed ordering and shipping information on page 6 of this data sheet.

#### THERMAL CHARACTERISTICS

Symbol	Parameter	Min	Max	Unit
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient*	-	60	°C/W

<sup>\*</sup>When mounted on the minimum pad size recommended (PCB Mount)

#### **ELECTRICAL CHARACTERISTICS** (T<sub>C</sub> = 25°C, unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
OFF CHAR	ACTERISTIC			•	•	•
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D$ = 250 $\mu$ A, $V_{GS}$ = 0 V, $T_J$ = 25°C	600	-	-	V
$\Delta BV_{DSS} / \Delta T_{J}$	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 μA, Referenced to 25°C	-	0.6	-	V/°C
I <sub>DSS</sub> Zero Gate Voltage Drain Current		V <sub>DS</sub> = 600 V, V <sub>GS</sub> = 0 V	-	-	25	μΑ
		V <sub>DS</sub> = 480 V, T <sub>C</sub> = 125°C	-	-	250	
I <sub>GSS</sub>	Gate to Body Leakage Current	V <sub>GS</sub> = ±30 V, V <sub>DS</sub> = 0 V	-	-	±100	nA
ON CHARA	CTERISTICS					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS} = V_{DS}$ , $I_D = 250 \mu A$	2.0	-	4.0	٧
R <sub>DS(on)</sub>	Static Drain to Source On-Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 0.1 A	-	9.3	11.5	Ω
9FS	Forward Transconductance	V <sub>DS</sub> = 40 V, I <sub>D</sub> = 0.1 A (Note 4)	_	0.75	-	S
DYNAMIC (	CHARACTERISTICS					
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V, f = 1.0 MHz	-	130	170	pF
C <sub>oss</sub>	Output Capacitance		-	19	25	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		-	3.5	6	pF
$Q_g$	Total Gate Charge at 10 V	V <sub>DS</sub> = 480 V, I <sub>D</sub> = 1 A, V <sub>GS</sub> = 10 V	-	4.8	6.2	nC
Q <sub>gs</sub>	Gate to Source Gate Charge	(Note 4 and 5)	-	0.7	-	nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge		-	2.7	-	nC
SWITCHING	G CHARACTERISTICS					
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD}$ = 300 V, $I_D$ = 1 A, $R_G$ = 25 $\Omega$	_	7	24	ns
t <sub>r</sub>	Turn-On Rise Time	(Note 4 and 5)	-	21	52	ns
t <sub>d(off)</sub>	Turn-Off Delay Time		-	13	36	ns
t <sub>f</sub>	Turn-Off Fall Time		-	27	64	ns
DRAIN-SO	URCE DIODE CHARACTERISTICS AND	MAXIMUM RATINGS				
I <sub>S</sub>	Maximum Continuous Drain to Source Diode Forward Current		-	-	0.2	Α
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current		-	-	0.8	Α
$V_{SD}$	Drain to Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 0.2 A	-	-	1.4	V
t <sub>rr</sub>	Reverse Recovery Time	$V_{GS} = 0 \text{ V, } I_{SD} = 1 \text{ A, } dI_F/dt = 100 \text{ A/}\mu\text{s}$	-	190	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	(Note 4)	_	0.53	-	μC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

- 4. Pulse Test: Pulse width  $\leq$  300  $\mu$ s, Duty Cycle  $\leq$  2%.
- 5. Essentially Independent of Operating Temperature Typical Characteristics.

#### **TYPICAL CHARACTERISTICS**

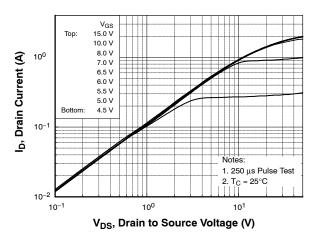


Figure 1. On-Region Characteristics

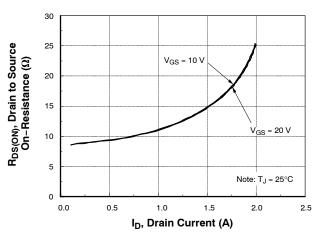


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

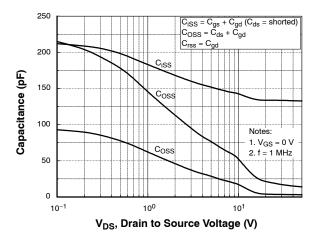


Figure 5. Capacitance Characteristics

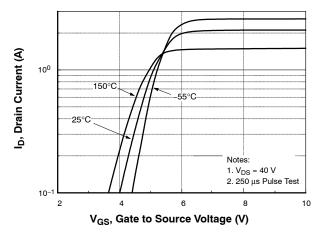


Figure 2. Transfer Characteristics

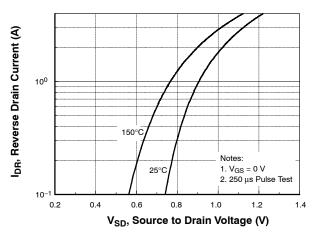


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

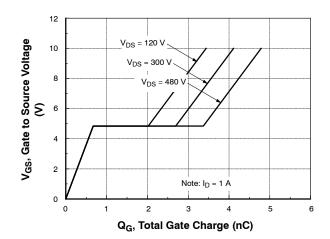


Figure 6. Gate Charge Characteristics

#### TYPICAL CHARACTERISTICS (Continued)

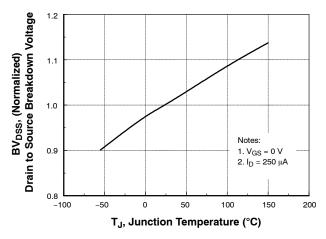


Figure 7. Breakdown Voltage Variation vs. Temperature

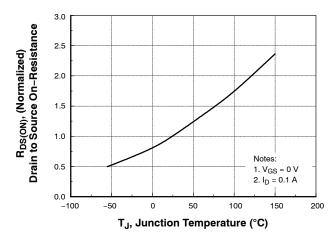


Figure 8. On–Resistance Variation vs. Temperature

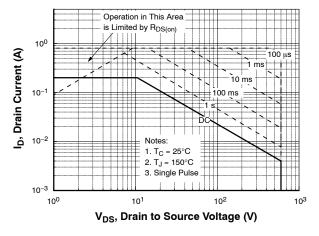


Figure 9. Maximum Safe Operating Area

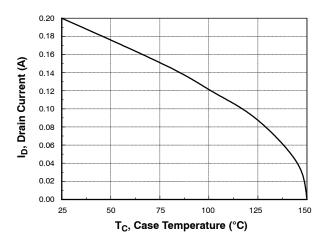


Figure 10. Maximum Drain Current vs. Case Temperature

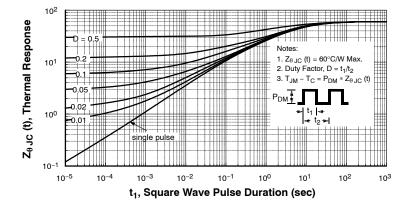


Figure 11. Transient Thermal Response Curve

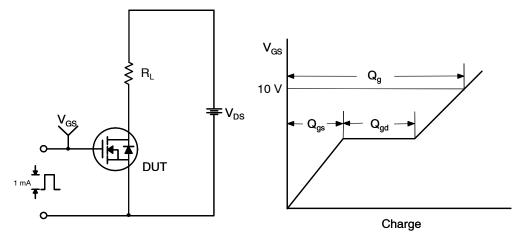


Figure 12. Gate Charge Test Circuit & Waveforms

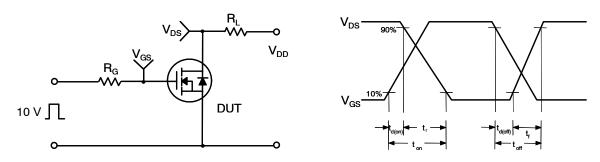


Figure 13. Resistive Switching Test Circuit & Waveforms

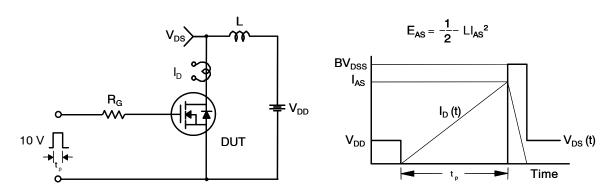
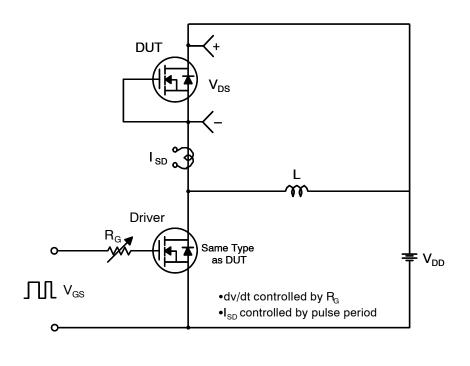


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms



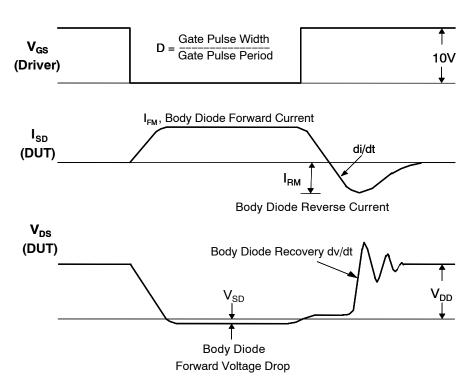


Figure 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms

## PACKAGE MARKING AND ORDERING INFORMATION

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FQT1N60C	FQT1N60CTF-WS	SOT-223	330 mm	12 mm	4000

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

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SCALE 2:1



A

В

□ 0.10 M | C | A | B |

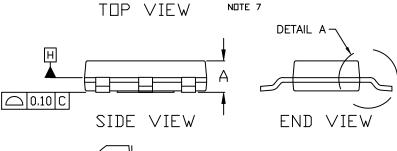
**DATE 13 MAY 2020** 

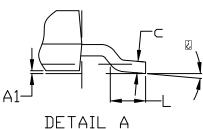
#### NOTES

- DIMENSIONING AND TOLERANCING PER ASME
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  Y14.5M, 2009.
  CONTROLLING DIMENSION: MILLIMETERS
  DIMENSIONS D & E1 ARE DETERMINED AT DATUM
  H. DIMENSIONS DO NOT INCLUDE MOLD FLASH,
  PROTRUSIONS DR GATE BURRS. SHALL NOT
  EXCEED 0.23mm PER SIDE.
  LEAD DIMENSIONS & AND &1 DO NOT INCLUDE
  DAMBAR PROTRUSION. ALLOWABLE DAMBBAR
  PROTRUSION IS 0.08mm PER SIDE.
  DATUMS A AND B ARE DETERMINED AT DATUM H.
  A1 IS DEFINED AS THE VERTICAL DISTANCE
  FROM THE SEATING PLANE TO THE LOWEST
  POINT OF THE PACKAGE BODY.
  POSITIONAL TOLERANCE APPLIES TO DIMENSIONS
  & AND &1.

- b AND b1.

	MILLIMETERS			
DIM	MIN.	N□M.	MAX.	
Α			1.80	
A1	0.02	0.06	0.11	
b	0.60	0.74	0.88	
b1	2.90	3.00	3.10	
c	0.24		0.35	
D	6.30	6.50	6.70	
E	6.70	7.00	7.30	
E1	3.30	3.50	3.70	
е	2.30 BSC			
L	0.25			
į.	0*		10°	





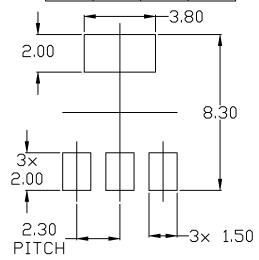




- = Assembly Location
- = Year
- = Work Week **W**
- XXXXX = Specific Device Code
- = Pb-Free Package

(Note: Microdot may be in either location)

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.



#### RECOMMENDED MOUNTING FOOTPRINT

For additional information on our Pb-Free strategy and soldering details, please download the IN Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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DESCRIPTION:	SOT-223		PAGE 1 OF 1	

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